



VOL. 238 NO. 3 (2004)
International Journal of
Mass Spectrometry

Editors

S.A. McLuckey
West Lafayette, IN

H. Schwarz
Berlin

Special Issue
Consultant

M.T. Bowers
Santa Barbara, CA

Editorial Board

P.B. Armentrout
Salt Lake City, UT

T. Baer
Chapel Hill, NC

J.S. Becker
Jülich

V.M. Bierbaum
Boulder, CO

B. Chait
New York, NY

D.K. Böhme
North York, Ont.

A.G. Brenton
Swansea

R.G. Cooks
West Lafayette, IN

S.J. Gaskell
Manchester

M.L. Gross
St. Louis, MO

J. Grotemeyer
Kiel

R.M.A. Heeren
Amsterdam

F. Hillenkamp
Münster

K.R. Jennings
Coventry

M. Kappes
Karlsruhe

C.B. Lebrilla
Davis, CA

C. Lifshitz
Jerusalem

S. Liu
Changchun

M. Mann
Odense

R.E. March
Peterborough, Ont.

T.D. Märk
Innsbruck

A.G. Marshall
Tallahassee, FL

T.B. McMahon
Waterloo, Ont.

H.J. Neusser
Garching

N.M.M. Nibbering
Amsterdam

R.A.J. O'Hair
Victoria

G. Ohanessian
Palaiseau

J.M. Riveros
São Paulo

M.T. Rodgers
Detroit, MI

C.A. Schalley
Bonn

J. Scrivens
Middlesborough

R. Smith
Richland, WA

M. Speranza
Rome

F. Tureček
Seattle, WA

E. Uggerud
Blindern

G. von Helden
Berlin

E.R. Williams
Berkeley, CA

H. Wollnik
Giessen

V.H. Wysocki
Tucson, AZ

R.A. Yost
Gainesville, FL

R. Zenobi
Zurich



Amsterdam • Boston • Jena •
London • New York • Oxford •
Paris • Philadelphia •
San Diego • St. Louis